

File View Edit Tools Window Help				2/5/05	
Drafts				[4:45 PM] [2/5/05] [2:00 PM] [2:00 PM] [2:00 PM]	
	Hit#	Search Text	DBs	Time St	
1	5733	chip same wafer same test	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2004/08/ 11:02	
2	14218	((clean or cleaning or cleaned) with (probe or needle or pin))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2004/08/ 11:03	
3	102	((chip same wafer same test) and ((clean or cleaning or cleaned) with (probe or needle or pin)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2004/08/ 11:33	
4	10042	257/48,E21.521,E21.524.ccls. 438/11,14,15,17,18,F0R101,F0R142.ccls. 716/4-6.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2004/08/ 11:29	
5	13	((chip same wafer same test) and ((clean or cleaning or cleaned) with (probe or needle or pin))) and (257/48,E21.521,E21.524.ccls. 438/11,14,15,17,18,F0R101,F0R142.ccls. 716/4-6.ccls.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/01/ 12:42	
6	1	((chip same wafer same test) and ((clean or cleaning or cleaned) with (probe or needle or pin))) and database	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/01/ 12:43	
7	29	((chip same wafer same test) and ((clean or cleaning or cleaned) same (probe or needle or pin))) and (257/48,E21.521,E21.524.ccls. 438/11,14,15,17,18,F0R101,F0R142.ccls. 716/4-6.ccls.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/01/ 12:43	
8	5	((chip same wafer same test) and ((clean or cleaning or cleaned) same (probe or needle or pin))) and (257/48,E21.521,E21.524.ccls. 438/11,14,15,17,18,F0R101,F0R142.ccls. 716/4-6.ccls.) and database	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/01/ 12:43	
9	0	((chip same wafer same test) and ((clean or cleaning or cleaned) with (probe or needle or pin))) and (257/48,E21.521,E21.524.ccls. 438/11,14,15,17,18,F0R101,F0R142.ccls. 716/4-6.ccls.) and @pd>"20040827"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/01/ 12:43	
10	0	((chip same wafer same test) and ((clean or cleaning or cleaned) with (probe or needle or pin))) and database and @pd>"20040827"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/01/ 12:43	
11	0	((chip same wafer same test) and ((clean or cleaning or cleaned) same (probe or needle or pin))) and (257/48,E21.521,E21.524.ccls. 438/11,14,15,17,18,F0R101,F0R142.ccls. 716/4-6.ccls.) and database and @pd>"20040827"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/01/ 12:43	
12	2	((chip same wafer same test) and ((clean or cleaning or cleaned) same (probe or needle or pin))) and (257/48,E21.521,E21.524.ccls. 438/11,14,15,17,18,F0R101,F0R142.ccls. 716/4-6.ccls.) and @pd>"20040827"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/01/ 12:44	
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